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### Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	2566
Number of Logic Elements/Cells	25660
Total RAM Bits	1944576
Number of I/O	597
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	780-BBGA
Supplier Device Package	780-FBGA (29x29)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/intel/ep1s25f780c6n">https://www.e-xfl.com/product-detail/intel/ep1s25f780c6n</a>

Chapter	Date/Version	Changes Made
2	July 2005 v3.2	<ul style="list-style-type: none"> <li>Added “Clear Signals” section.</li> <li>Updated “Power Sequencing &amp; Hot Socketing” section.</li> <li>Format changes.</li> </ul>
	September 2004, v3.1	<ul style="list-style-type: none"> <li>Updated fast regional clock networks description on <a href="#">page 2–73</a>.</li> <li>Deleted the word preliminary from the “specification for the maximum time to relock is 100 <math>\mu</math>s” on <a href="#">page 2–90</a>.</li> <li>Added information about differential SSTL and HSTL outputs in “External Clock Outputs” on <a href="#">page 2–92</a>.</li> <li>Updated notes in <a href="#">Figure 2–55</a> on <a href="#">page 2–93</a>.</li> <li>Added information about <i>m</i> counter to “Clock Multiplication &amp; Division” on <a href="#">page 2–101</a>.</li> <li>Updated Note 1 in <a href="#">Table 2–58</a> on <a href="#">page 2–101</a>.</li> <li>Updated description of “Clock Multiplication &amp; Division” on <a href="#">page 2–88</a>.</li> <li>Updated <a href="#">Table 2–22</a> on <a href="#">page 2–102</a>.</li> <li>Added references to AN 349 and AN 329 to “External RAM Interfacing” on <a href="#">page 2–115</a>.</li> <li><a href="#">Table 2–25</a> on <a href="#">page 2–116</a>: updated the table, updated Notes 3 and 4. Notes 4, 5, and 6, are now Notes 5, 6, and 7, respectively.</li> <li>Updated <a href="#">Table 2–26</a> on <a href="#">page 2–117</a>.</li> <li>Added information about PCI Compliance to <a href="#">page 2–120</a>.</li> <li><a href="#">Table 2–32</a> on <a href="#">page 2–126</a>: updated the table and deleted Note 1.</li> <li>Updated reference to device pin-outs now being available on the web on <a href="#">page 2–130</a>.</li> <li>Added Notes 4 and 5 to <a href="#">Table 2–36</a> on <a href="#">page 2–130</a>.</li> <li>Updated Note 3 in <a href="#">Table 2–37</a> on <a href="#">page 2–131</a>.</li> <li>Updated Note 5 in <a href="#">Table 2–41</a> on <a href="#">page 2–135</a>.</li> </ul>
	April 2004, v3.0	<ul style="list-style-type: none"> <li>Added note 3 to rows 11 and 12 in <a href="#">Table 2–18</a>.</li> <li>Deleted “Stratix and Stratix GX Device PLL Availability” table.</li> <li>Added I/O standards row in <a href="#">Table 2–28</a> that support max and min strength.</li> <li>Row <code>clk [1,3,8,10]</code> was removed from <a href="#">Table 2–30</a>.</li> <li>Added checkmarks in Enhanced column for LVPECL, 3.3-V PCML, LVDS, and HyperTransport technology rows in <a href="#">Table 2–32</a>.</li> <li>Removed the Left and Right I/O Banks row in <a href="#">Table 2–34</a>.</li> <li>Changed RCLK values in <a href="#">Figures 2–50</a> and <a href="#">2–51</a>.</li> <li>External RAM Interfacing section replaced.</li> </ul>
	November 2003, v2.2	<ul style="list-style-type: none"> <li>Added 672-pin BGA package information in <a href="#">Table 2–37</a>.</li> <li>Removed support for series and parallel on-chip termination.</li> <li>Termination Technology renamed differential on-chip termination.</li> <li>Updated the number of channels per PLL in <a href="#">Tables 2–38</a> through <a href="#">2–42</a>.</li> <li>Updated <a href="#">Figures 2–65</a> and <a href="#">2–67</a>.</li> </ul>
	October 2003, v2.1	<ul style="list-style-type: none"> <li>Updated DDR I information.</li> <li>Updated <a href="#">Table 2–22</a>.</li> <li>Added <a href="#">Tables 2–25</a>, <a href="#">2–29</a>, <a href="#">2–30</a>, and <a href="#">2–72</a>.</li> <li>Updated <a href="#">Figures 2–59</a>, <a href="#">2–65</a>, and <a href="#">2–67</a>.</li> <li>Updated the Lock Detect section.</li> </ul>

Stratix devices are available in space-saving FineLine BGA® and ball-grid array (BGA) packages (see [Tables 1–3](#) through [1–5](#)). All Stratix devices support vertical migration within the same package (for example, you can migrate between the EP1S10, EP1S20, and EP1S25 devices in the 672-pin BGA package). Vertical migration means that you can migrate to devices whose dedicated pins, configuration pins, and power pins are the same for a given package across device densities. For I/O pin migration across densities, you must cross-reference the available I/O pins using the device pin-outs for all planned densities of a given package type to identify which I/O pins are migrational. The Quartus® II software can automatically cross reference and place all pins except differential pins for migration when given a device migration list. You must use the pin-outs for each device to verify the differential placement migration. A future version of the Quartus II software will support differential pin migration.

**Table 1–3. Stratix Package Options & I/O Pin Counts**

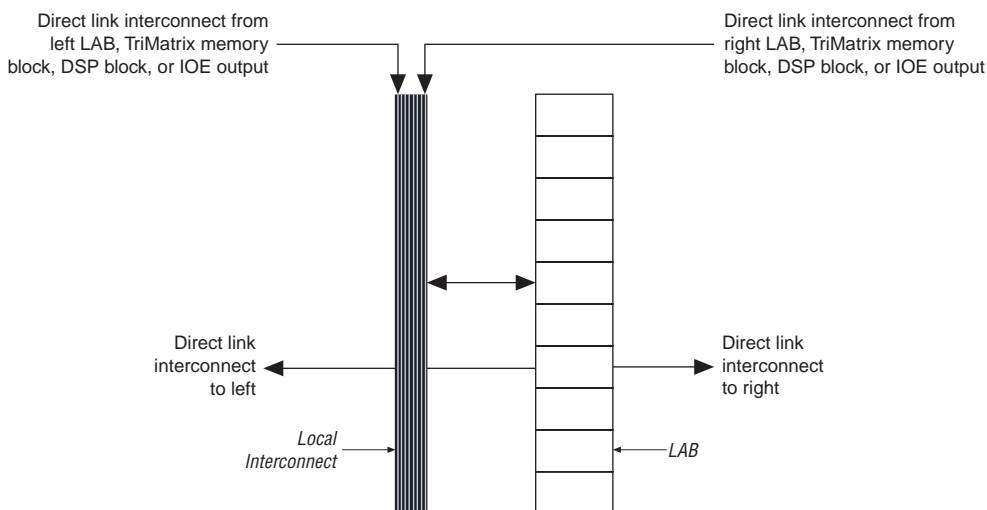
Device	672-Pin BGA	956-Pin BGA	484-Pin FineLine BGA	672-Pin FineLine BGA	780-Pin FineLine BGA	1,020-Pin FineLine BGA	1,508-Pin FineLine BGA
EP1S10	345		335	345	426		
EP1S20	426		361	426	586		
EP1S25	473			473	597	706	
EP1S30		683			597	726	
EP1S40		683			615	773	822
EP1S60		683				773	1,022
EP1S80		683				773	1,203

**Note to [Table 1–3](#):**

- (1) All I/O pin counts include 20 dedicated clock input pins (clk[15..0]p, clk0n, clk2n, clk9n, and clk11n) that can be used for data inputs.

**Table 1–4. Stratix BGA Package Sizes**

Dimension	672 Pin	956 Pin
Pitch (mm)	1.27	1.27
Area (mm <sup>2</sup> )	1,225	1,600
Length × width (mm × mm)	35 × 35	40 × 40

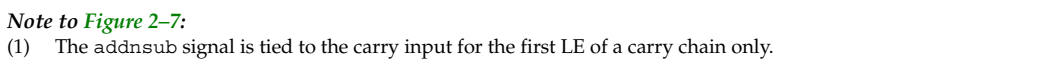
**Figure 2–3. Direct Link Connection**

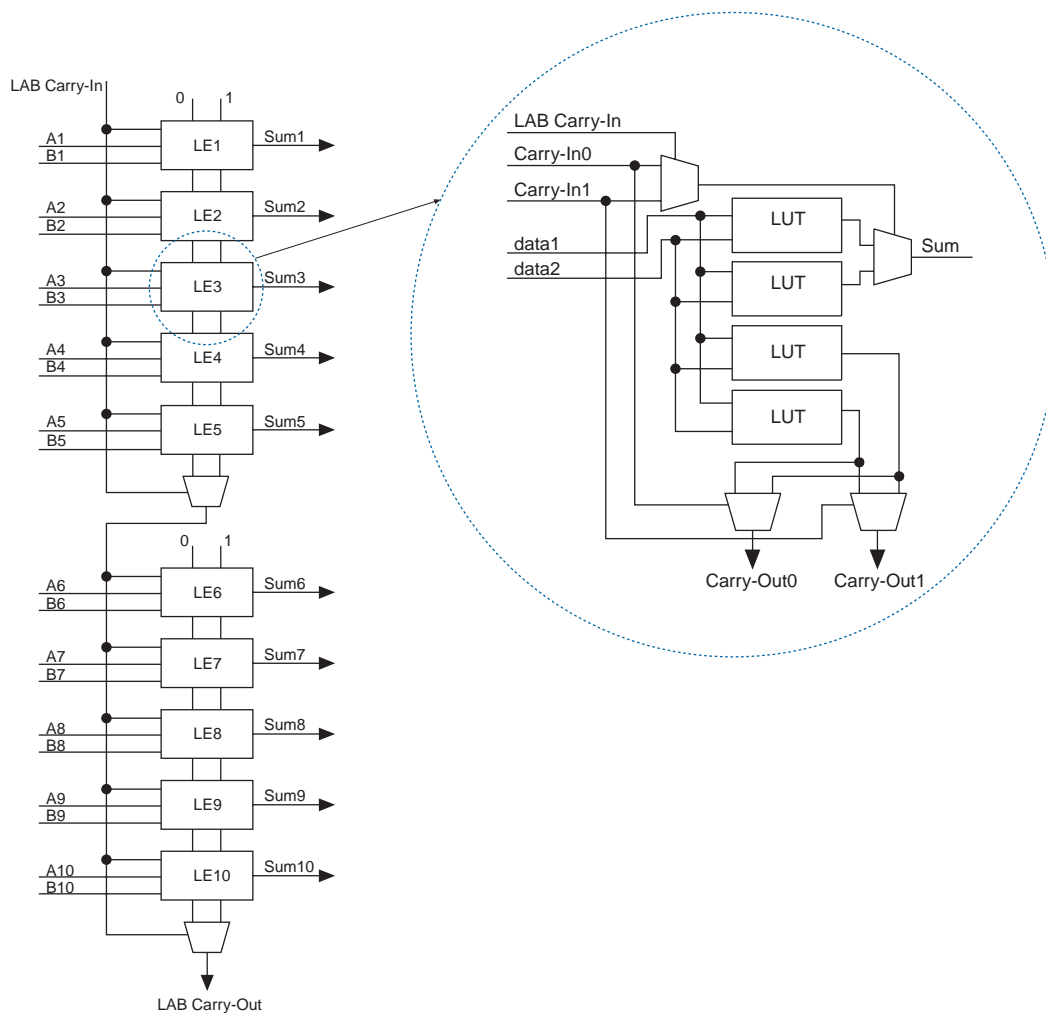
## LAB Control Signals

Each LAB contains dedicated logic for driving control signals to its LEs. The control signals include two clocks, two clock enables, two asynchronous clears, synchronous clear, asynchronous preset/load, synchronous load, and add/subtract control signals. This gives a maximum of 10 control signals at a time. Although synchronous load and clear signals are generally used when implementing counters, they can also be used with other functions.

Each LAB can use two clocks and two clock enable signals. Each LAB's clock and clock enable signals are linked. For example, any LE in a particular LAB using the `labclk1` signal will also use `labckena1`. If the LAB uses both the rising and falling edges of a clock, it also uses both LAB-wide clock signals. De-asserting the clock enable signal will turn off the LAB-wide clock.

Each LAB can use two asynchronous clear signals and an asynchronous load/preset signal. The asynchronous load acts as a preset when the asynchronous load data input is tied high.



**Figure 2–8. Carry Select Chain**

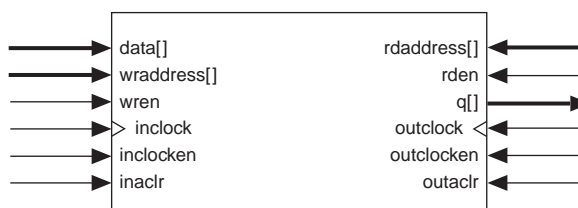
## Clear & Preset Logic Control

LAB-wide signals control the logic for the register's clear and preset signals. The LE directly supports an asynchronous clear and preset function. The register preset is achieved through the asynchronous load of a logic high. The direct asynchronous preset does not require a NOT-gate push-back technique. Stratix devices support simultaneous preset/

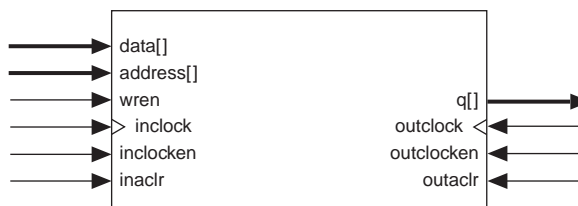
In addition to true dual-port memory, the memory blocks support simple dual-port and single-port RAM. Simple dual-port memory supports a simultaneous read and write and can either read old data before the write occurs or just read the don't care bits. Single-port memory supports non-simultaneous reads and writes, but the `q[]` port will output the data once it has been written to the memory (if the outputs are not registered) or after the next rising edge of the clock (if the outputs are registered). For more information, see [Chapter 2, TriMatrix Embedded Memory Blocks in Stratix & Stratix GX Devices](#) of the *Stratix Device Handbook, Volume 2*. [Figure 2–13](#) shows these different RAM memory port configurations for TriMatrix memory.

**Figure 2–13. Simple Dual-Port & Single-Port Memory Configurations**

#### Simple Dual-Port Memory



#### Single-Port Memory (1)



#### Note to Figure 2–13:

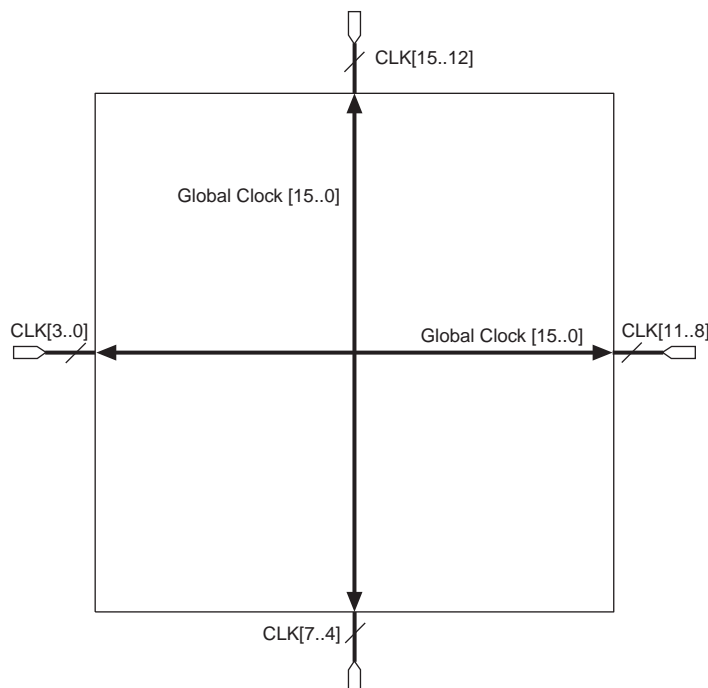
- (1) Two single-port memory blocks can be implemented in a single M4K block as long as each of the two independent block sizes is equal to or less than half of the M4K block size.

The memory blocks also enable mixed-width data ports for reading and writing to the RAM ports in dual-port RAM configuration. For example, the memory block can be written in  $\times 1$  mode at port A and read out in  $\times 16$  mode from port B.

## Read/Write Clock Mode

The memory blocks implement read/write clock mode for simple dual-port memory. You can use up to two clocks in this mode. The write clock controls the block's data inputs, *wraddress*, and *wren*. The read clock controls the data output, *rdaddress*, and *rden*. The memory blocks support independent clock enables for each clock and asynchronous clear signals for the read- and write-side registers. [Figure 2–27](#) shows a memory block in read/write clock mode.



**Figure 2–42. Global Clock** *Note (1)***Note to Figure 2–42:**

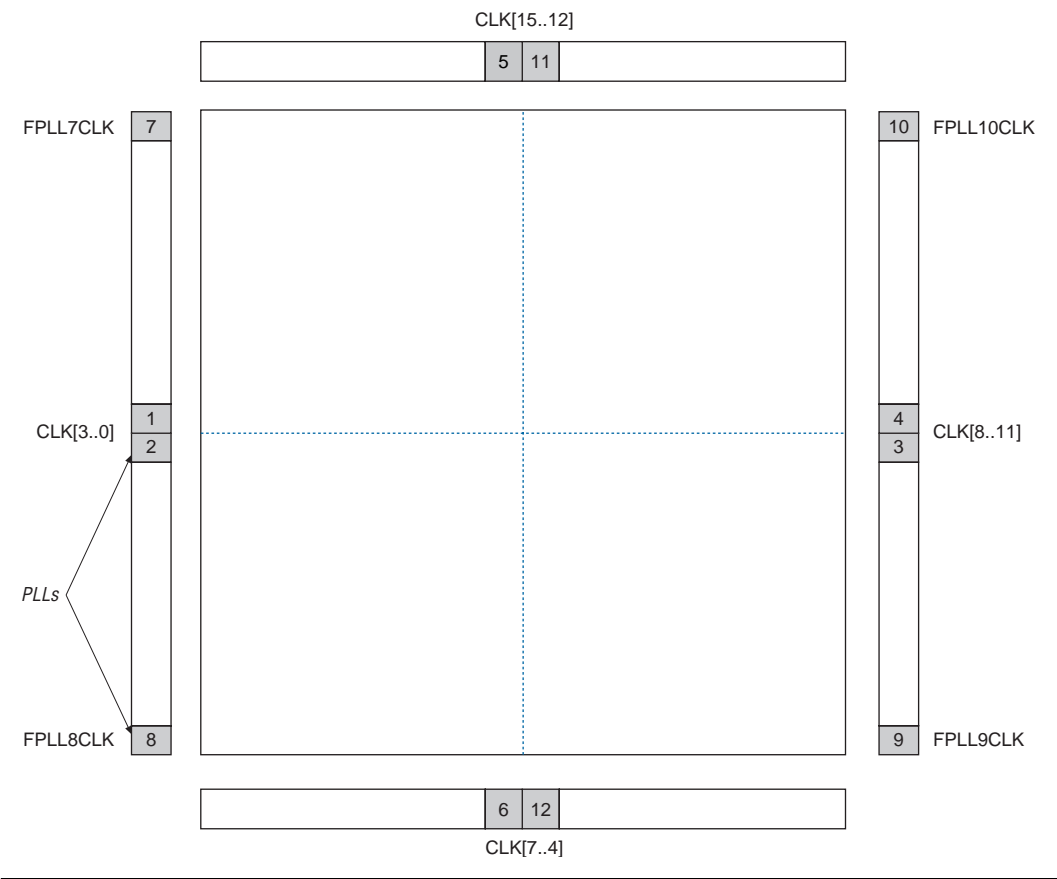
- (1) The corner fast PLLs can also be driven through the global or regional clock networks. The global or regional clock input to the fast PLL can be driven by an output from another PLL, a pin-driven global or regional clock, or internally-generated global signals.

**Regional Clock Network**

There are four regional clock networks within each quadrant of the Stratix device that are driven by the same dedicated  $\text{CLK}[15..0]$  input pins or from PLL outputs. From a top view of the silicon,  $\text{RCLK}[0..3]$  are in the top left quadrant,  $\text{RCLK}[8..11]$  are in the top-right quadrant,  $\text{RCLK}[4..7]$  are in the bottom-left quadrant, and  $\text{RCLK}[12..15]$  are in the bottom-right quadrant. The regional clock networks only pertain to the quadrant they drive into. The regional clock networks provide the lowest clock delay and skew for logic contained within a single quadrant.  $\text{RCLK}$  cannot be driven by internal logic. The  $\text{CLK}$  clock pins symmetrically drive the  $\text{RCLK}$  networks within a particular quadrant, as shown in Figure 2–43. See Figures 2–50 and 2–51 for  $\text{RCLK}$  connections from PLLs and  $\text{CLK}$  pins.

Figure 2–49 shows a top-level diagram of the Stratix device and PLL floorplan.

Figure 2–49. PLL Locations



**Table 2–27. DQS & DQ Bus Mode Support** (Part 2 of 2) *Note (1)*

Device	Package	Number of ×8 Groups	Number of ×16 Groups	Number of ×32 Groups
EP1S25	672-pin BGA 672-pin FineLine BGA	16 (3)	8	4
	780-pin FineLine BGA 1,020-pin FineLine BGA	20	8	4
EP1S30	956-pin BGA 780-pin FineLine BGA 1,020-pin FineLine BGA	20	8	4
EP1S40	956-pin BGA 1,020-pin FineLine BGA 1,508-pin FineLine BGA	20	8	4
EP1S60	956-pin BGA 1,020-pin FineLine BGA 1,508-pin FineLine BGA	20	8	4
EP1S80	956-pin BGA 1,508-pin FineLine BGA 1,923-pin FineLine BGA	20	8	4

**Notes to Table 2–27:**

- (1) See the *Selectable I/O Standards in Stratix & Stratix GX Devices* chapter in the *Stratix Device Handbook, Volume 2* for  $V_{REF}$  guidelines.
- (2) These packages have six groups in I/O banks 3 and 4 and six groups in I/O banks 7 and 8.
- (3) These packages have eight groups in I/O banks 3 and 4 and eight groups in I/O banks 7 and 8.
- (4) This package has nine groups in I/O banks 3 and 4 and nine groups in I/O banks 7 and 8.
- (5) These packages have three groups in I/O banks 3 and 4 and four groups in I/O banks 7 and 8.

A compensated delay element on each DQS pin automatically aligns input DQS synchronization signals with the data window of their corresponding DQ data signals. The DQS signals drive a local DQS bus in the top and bottom I/O banks. This DQS bus is an additional resource to the I/O clocks and is used to clock DQ input registers with the DQS signal.

Two separate single phase-shifting reference circuits are located on the top and bottom of the Stratix device. Each circuit is driven by a system reference clock through the CLK pins that is the same frequency as the DQS signal. Clock pins CLK [15 . . 12] p feed the phase-shift circuitry on the top of the device and clock pins CLK [7 . . 4] p feed the phase-shift circuitry on the bottom of the device. The phase-shifting reference circuit on the top of the device controls the compensated delay elements for all 10 DQS pins located at the top of the device. The phase-shifting reference circuit on the bottom of the device controls the compensated delay elements for all 10 DQS pins located on the bottom of the device. All 10 delay elements (DQS signals) on either the top or bottom of the device

- 1.8-V HSTL Class I and II
- SSTL-3 Class I and II
- SSTL-2 Class I and II
- SSTL-18 Class I and II
- CTT

Table 2–31 describes the I/O standards supported by Stratix devices.

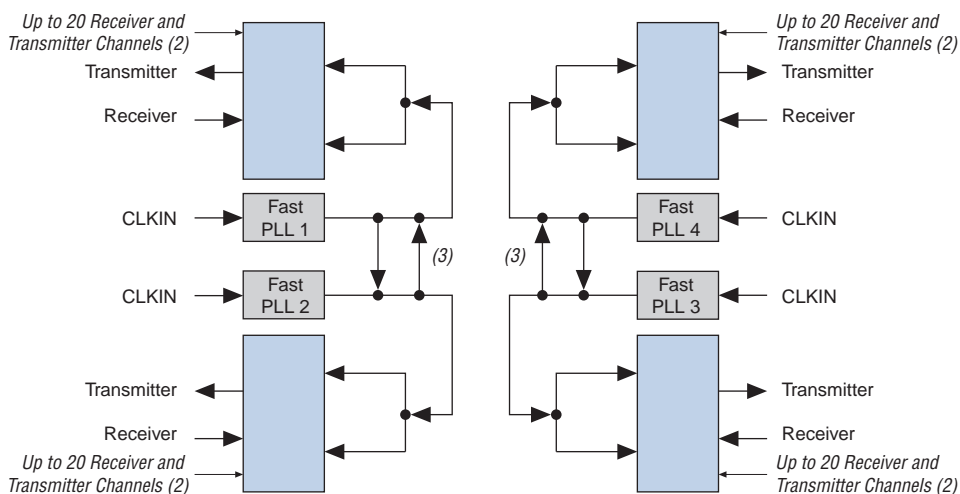
<b>Table 2–31. Stratix Supported I/O Standards</b>				
<b>I/O Standard</b>	<b>Type</b>	<b>Input Reference Voltage (<math>V_{REF}</math>) (V)</b>	<b>Output Supply Voltage (<math>V_{CCIO}</math>) (V)</b>	<b>Board Termination Voltage (<math>V_{TT}</math>) (V)</b>
LVTTTL	Single-ended	N/A	3.3	N/A
LVC MOS	Single-ended	N/A	3.3	N/A
2.5 V	Single-ended	N/A	2.5	N/A
1.8 V	Single-ended	N/A	1.8	N/A
1.5 V	Single-ended	N/A	1.5	N/A
3.3-V PCI	Single-ended	N/A	3.3	N/A
3.3-V PCI-X 1.0	Single-ended	N/A	3.3	N/A
LVDS	Differential	N/A	3.3	N/A
LVPECL	Differential	N/A	3.3	N/A
3.3-V PCML	Differential	N/A	3.3	N/A
HyperTransport	Differential	N/A	2.5	N/A
Differential HSTL (1)	Differential	0.75	1.5	0.75
Differential SSTL (2)	Differential	1.25	2.5	1.25
GTL	Voltage-referenced	0.8	N/A	1.20
GTL+	Voltage-referenced	1.0	N/A	1.5
1.5-V HSTL Class I and II	Voltage-referenced	0.75	1.5	0.75
1.8-V HSTL Class I and II	Voltage-referenced	0.9	1.8	0.9
SSTL-18 Class I and II	Voltage-referenced	0.90	1.8	0.90
SSTL-2 Class I and II	Voltage-referenced	1.25	2.5	1.25
SSTL-3 Class I and II	Voltage-referenced	1.5	3.3	1.5
AGP (1× and 2°)	Voltage-referenced	1.32	3.3	N/A
CTT	Voltage-referenced	1.5	3.3	1.5

**Notes to Table 2–31:**

- (1) This I/O standard is only available on input and output clock pins.  
 (2) This I/O standard is only available on output column clock pins.

The Quartus II MegaWizard® Plug-In Manager only allows the implementation of up to 20 receiver or 20 transmitter channels for each fast PLL. These channels operate at up to 840 Mbps. The receiver and transmitter channels are interleaved such that each I/O bank on the left and right side of the device has one receiver channel and one transmitter channel per LAB row. [Figure 2-74](#) shows the fast PLL and channel layout in EP1S10, EP1S20, and EP1S25 devices. [Figure 2-75](#) shows the fast PLL and channel layout in the EP1S30 to EP1S80 devices.

**Figure 2-74. Fast PLL & Channel Layout in the EP1S10, EP1S20 or EP1S25 Devices** *Note (1)*



**Notes to Figure 2-74:**

- (1) Wire-bond packages support up to 624 Mbps.
- (2) See [Table 2-41](#) for the number of channels each device supports.
- (3) There is a multiplexer here to select the PLL clock source. If a PLL uses this multiplexer to clock channels outside of its bank quadrant, those clocked channels support up to 840 Mbps for “high” speed channels and 462 Mbps for “low” speed channels, as labeled in the device pin-outs at [www.altera.com](http://www.altera.com).

**Table 3–1. Stratix JTAG Instructions**

JTAG Instruction	Instruction Code	Description
SAMPLE/PRELOAD	00 0000 0101	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern to be output at the device pins. Also used by the SignalTap II embedded logic analyzer.
EXTEST (1)	00 0000 0000	Allows the external circuitry and board-level interconnects to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
BYPASS	11 1111 1111	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation.
USERCODE	00 0000 0111	Selects the 32-bit USERCODE register and places it between the TDI and TDO pins, allowing the USERCODE to be serially shifted out of TDO.
IDCODE	00 0000 0110	Selects the IDCODE register and places it between TDI and TDO, allowing the IDCODE to be serially shifted out of TDO.
HIGHZ (1)	00 0000 1011	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation, while tri-stating all of the I/O pins.
CLAMP (1)	00 0000 1010	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation while holding I/O pins to a state defined by the data in the boundary-scan register.
ICR instructions		Used when configuring an Stratix device via the JTAG port with a MasterBlaster™, ByteBlasterMV™, or ByteBlaster™ II download cable, or when using a Jam File or Jam Byte-Code File via an embedded processor or JRunner.
PULSE_NCONFIG	00 0000 0001	Emulates pulsing the nCONFIG pin low to trigger reconfiguration even though the physical pin is unaffected.
CONFIG_IO	00 0000 1101	Allows configuration of I/O standards through the JTAG chain for JTAG testing. Can be executed before, after, or during configuration. Stops configuration if executed during configuration. Once issued, the CONFIG_IO instruction will hold nSTATUS low to reset the configuration device. nSTATUS is held low until the device is reconfigured.
SignalTap II instructions		Monitors internal device operation with the SignalTap II embedded logic analyzer.

**Note to Table 3–1:**

- (1) Bus hold and weak pull-up resistor features override the high-impedance state of HIGHZ, CLAMP, and EXTEST.

**Table 4–2. Stratix Device Recommended Operating Conditions (Part 2 of 2)**

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
$V_{CCIO}$	Supply voltage for output buffers, 3.3-V operation	(4), (5)	3.00 (3.135)	3.60 (3.465)	V
	Supply voltage for output buffers, 2.5-V operation	(4)	2.375	2.625	V
	Supply voltage for output buffers, 1.8-V operation	(4)	1.71	1.89	V
	Supply voltage for output buffers, 1.5-V operation	(4)	1.4	1.6	V
$V_I$	Input voltage	(3), (6)	–0.5	4.0	V
$V_O$	Output voltage		0	$V_{CCIO}$	V
$T_J$	Operating junction temperature	For commercial use	0	85	°C
		For industrial use	–40	100	°C

**Table 4–3. Stratix Device DC Operating Conditions Note (7) (Part 1 of 2)**

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
$I_I$	Input pin leakage current	$V_I = V_{CCIOmax}$ to 0 V (8)	–10		10	μA
$I_{OZ}$	Tri-stated I/O pin leakage current	$V_O = V_{CCIOmax}$ to 0 V (8)	–10		10	μA
$I_{CC0}$	$V_{CC}$ supply current (standby) (All memory blocks in power-down mode)	$V_I$ = ground, no load, no toggling inputs				mA
		EP1S10. $V_I$ = ground, no load, no toggling inputs		37		mA
		EP1S20. $V_I$ = ground, no load, no toggling inputs		65		mA
		EP1S25. $V_I$ = ground, no load, no toggling inputs		90		mA
		EP1S30. $V_I$ = ground, no load, no toggling inputs		114		mA
		EP1S40. $V_I$ = ground, no load, no toggling inputs		145		mA
		EP1S60. $V_I$ = ground, no load, no toggling inputs		200		mA
		EP1S80. $V_I$ = ground, no load, no toggling inputs		277		mA

**Table 4–36. Stratix Performance (Part 2 of 2) Notes (1), (2)**

Applications		Resources Used			Performance				
		LEs	TriMatrix Memory Blocks	DSP Blocks	-5 Speed Grade	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Units
TriMatrix memory M-RAM block	True dual-port RAM 16K × 36 bit	0	1	0	269.83	237.69	206.82	175.74	MHz
	Single port RAM 32K × 18 bit	0	1	0	275.86	244.55	212.76	180.83	MHz
	Simple dual-port RAM 32K × 18 bit	0	1	0	275.86	244.55	212.76	180.83	MHz
	True dual-port RAM 32K × 18 bit	0	1	0	275.86	244.55	212.76	180.83	MHz
	Single port RAM 64K × 9 bit	0	1	0	287.85	253.29	220.36	187.26	MHz
	Simple dual-port RAM 64K × 9 bit	0	1	0	287.85	253.29	220.36	187.26	MHz
	True dual-port RAM 64K × 9 bit	0	1	0	287.85	253.29	220.36	187.26	MHz
DSP block	9 × 9-bit multiplier (3)	0	0	1	335.0	293.94	255.68	217.24	MHz
	18 × 18-bit multiplier (4)	0	0	1	278.78	237.41	206.52	175.50	MHz
	36 × 36-bit multiplier (4)	0	0	1	148.25	134.71	117.16	99.59	MHz
	36 × 36-bit multiplier (5)	0	0	1	278.78	237.41	206.52	175.5	MHz
	18-bit, 4-tap FIR filter	0	0	1	278.78	237.41	206.52	175.50	MHz
Larger Designs	8-bit, 16-tap parallel FIR filter	58	0	4	141.26	133.49	114.88	100.28	MHz
	8-bit, 1,024-point FFT function	870	5	1	261.09	235.51	205.21	175.22	MHz

**Notes to Table 4–36:**

- (1) These design performance numbers were obtained using the Quartus II software.
- (2) Numbers not listed will be included in a future version of the data sheet.
- (3) This application uses registered inputs and outputs.
- (4) This application uses registered multiplier input and output stages within the DSP block.
- (5) This application uses registered multiplier input, pipeline, and output stages within the DSP block.



**Table 4–41. M4K Block Internal Timing Microparameter Descriptions (Part 2 of 2)**

Symbol	Parameter
$t_{M4KDATAAH}$	A port data hold time after clock
$t_{M4KADDRASU}$	A port address setup time before clock
$t_{M4KADDRAH}$	A port address hold time after clock
$t_{M4KDATABSU}$	B port data setup time before clock
$t_{M4KDATABH}$	B port data hold time after clock
$t_{M4KADDRBSU}$	B port address setup time before clock
$t_{M4KADDRBH}$	B port address hold time after clock
$t_{M4KDATAO1}$	Clock-to-output delay when using output registers
$t_{M4KDATAO2}$	Clock-to-output delay without output registers
$t_{M4KCLKHL}$	Register minimum clock high or low time. This is a limit on the min time for the clock on the registers in these blocks. The actual performance is dependent upon the internal point-to-point delays in the blocks and may give slower performance as shown in <a href="#">Table 4–36 on page 4–20</a> and as reported by the timing analyzer in the Quartus II software.
$t_{M4KCLR}$	Minimum clear pulse width

**Table 4–42. M-RAM Block Internal Timing Microparameter Descriptions (Part 1 of 2)**

Symbol	Parameter
$t_{MRAMRC}$	Synchronous read cycle time
$t_{MRAMWC}$	Synchronous write cycle time
$t_{MRAMWERESU}$	Write or read enable setup time before clock
$t_{MRAMWEREH}$	Write or read enable hold time after clock
$t_{MRAMCLKENSU}$	Clock enable setup time before clock
$t_{MRAMCLKENH}$	Clock enable hold time after clock
$t_{MRAMBESU}$	Byte enable setup time before clock
$t_{MRAMBEH}$	Byte enable hold time after clock
$t_{MRAMDATAASU}$	A port data setup time before clock
$t_{MRAMDATAAH}$	A port data hold time after clock
$t_{MRAMADDRASU}$	A port address setup time before clock
$t_{MRAMADDRAH}$	A port address hold time after clock
$t_{MRAMDATABSU}$	B port setup time before clock

**Table 4–71. EP1S25 External I/O Timing on Row Pins Using Regional Clock Networks**

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
$t_{\text{INSU}}$	1.793		1.927		2.182		2.542		ns
$t_{\text{INH}}$	0.000		0.000		0.000		0.000		ns
$t_{\text{OUTCO}}$	2.759	5.457	2.759	5.835	2.759	6.346	2.759	7.024	ns
$t_{\text{XZ}}$	2.786	5.511	2.786	5.891	2.786	6.414	2.786	7.106	ns
$t_{\text{ZX}}$	2.786	5.511	2.786	5.891	2.786	6.414	2.786	7.106	ns
$t_{\text{INSUPLL}}$	1.169		1.221		1.373		1.600		ns
$t_{\text{INHPLL}}$	0.000		0.000		0.000		0.000		ns
$t_{\text{OUTCOPLL}}$	1.375	2.861	1.375	2.999	1.375	3.082	1.375	3.174	ns
$t_{\text{XZPLL}}$	1.402	2.915	1.402	3.055	1.402	3.150	1.402	3.256	ns
$t_{\text{ZXPLL}}$	1.402	2.915	1.402	3.055	1.402	3.150	1.402	3.256	ns

**Table 4–72. EP1S25 External I/O Timing on Row Pins Using Global Clock Networks**

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
$t_{\text{INSU}}$	1.665		1.779		2.012		2.372		ns
$t_{\text{INH}}$	0.000		0.000		0.000		0.000		ns
$t_{\text{OUTCO}}$	2.834	5.585	2.834	5.983	2.834	6.516	2.834	7.194	ns
$t_{\text{XZ}}$	2.861	5.639	2.861	6.039	2.861	6.584	2.861	7.276	ns
$t_{\text{ZX}}$	2.861	5.639	2.861	6.039	2.861	6.584	2.861	7.276	ns
$t_{\text{INSUPLL}}$	1.538		1.606		1.816		2.121		ns
$t_{\text{INHPLL}}$	0.000		0.000		0.000		0.000		ns
$t_{\text{OUTCOPLL}}$	1.164	2.492	1.164	2.614	1.164	2.639	1.164	2.653	ns
$t_{\text{XZPLL}}$	1.191	2.546	1.191	2.670	1.191	2.707	1.191	2.735	ns
$t_{\text{ZXPLL}}$	1.191	2.546	1.191	2.670	1.191	2.707	1.191	2.735	ns

**Table 4–93. EP1S80 External I/O Timing on Column Pins Using Global Clock Networks** *Note (1)*

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
$t_{\text{INSU}}$	0.884		0.976		1.118		NA		ns
$t_{\text{INH}}$	0.000		0.000		0.000		NA		ns
$t_{\text{OUTCO}}$	3.267	6.274	3.267	6.721	3.267	7.415	NA	NA	ns
$t_{\text{xZ}}$	3.207	6.148	3.207	6.589	3.207	7.291	NA	NA	ns
$t_{\text{ZX}}$	3.207	6.148	3.207	6.589	3.207	7.291	NA	NA	ns
$t_{\text{INSUPLL}}$	0.506		0.656		0.838		NA		ns
$t_{\text{INHPLL}}$	0.000		0.000		0.000		NA		ns
$t_{\text{OUTCOPLL}}$	1.635	2.805	1.635	2.809	1.635	2.828	NA	NA	ns
$t_{\text{xZPLL}}$	1.575	2.679	1.575	2.677	1.575	2.704	NA	NA	ns
$t_{\text{ZXPLL}}$	1.575	2.679	1.575	2.677	1.575	2.704	NA	NA	ns

**Table 4–94. EP1S80 External I/O Timing on Row Pins Using Fast Regional Clock Networks** *Note (1)*

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
$t_{\text{INSU}}$	2.792		2.993		3.386		NA		ns
$t_{\text{INH}}$	0.000		0.000		0.000		NA		ns
$t_{\text{OUTCO}}$	2.619	5.235	2.619	5.609	2.619	6.086	NA	NA	ns
$t_{\text{xZ}}$	2.646	5.289	2.646	5.665	2.646	6.154	NA	NA	ns
$t_{\text{ZX}}$	2.646	5.289	2.646	5.665	2.646	6.154	NA	NA	ns

Tables 4–125 and 4–126 show the high-speed I/O timing for Stratix devices.

<b>Table 4–125. High-Speed I/O Specifications for Flip-Chip Packages (Part 1 of 4) Notes (1), (2)</b>														
Symbol	Conditions	-5 Speed Grade			-6 Speed Grade			-7 Speed Grade			-8 Speed Grade			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f <sub>HSCLK</sub> (Clock frequency) (LVDS, LVPECL, HyperTransport technology) f <sub>HSCLK</sub> = f <sub>HSDR</sub> / W	W = 4 to 30 (Serdes used)	10		210	10		210	10		156	10		115.5	MHz
	W = 2 (Serdes bypass)	50		231	50		231	50		231	50		231	MHz
	W = 2 (Serdes used)	150		420	150		420	150		312	150		231	MHz
	W = 1 (Serdes bypass)	100		462	100		462	100		462	100		462	MHz
	W = 1 (Serdes used)	300		717	300		717	300		624	300		462	MHz
f <sub>HSDR</sub> Device operation (LVDS, LVPECL, HyperTransport technology)	J = 10	300		840	300		840	300		640	300		462	Mbps
	J = 8	300		840	300		840	300		640	300		462	Mbps
	J = 7	300		840	300		840	300		640	300		462	Mbps
	J = 4	300		840	300		840	300		640	300		462	Mbps
	J = 2	100		462	100		462	100		640	100		462	Mbps
	J = 1 (LVDS and LVPECL only)	100		462	100		462	100		640	100		462	Mbps

**Table 4–129. Enhanced PLL Specifications for -7 Speed Grade (Part 2 of 2)**

Symbol	Parameter	Min	Typ	Max	Unit
$t_{\text{OUTDUTY}}$	Duty cycle for external clock output (when set to 50%)	45		55	%
$t_{\text{JITTER}}$	Period jitter for external clock output (6)			$\pm 100$ ps for >200-MHz $\text{outclk}$ $\pm 20$ mUI for <200-MHz $\text{outclk}$	ps or mUI
$t_{\text{CONFIG5,6}}$	Time required to reconfigure the scan chains for PLLs 5 and 6			$289/f_{\text{SCANCLK}}$	
$t_{\text{CONFIG11,12}}$	Time required to reconfigure the scan chains for PLLs 11 and 12			$193/f_{\text{SCANCLK}}$	
$t_{\text{SCANCLK}}$	$\text{scanclk}$ frequency (5)			22	MHz
$t_{\text{DLOCK}}$	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays) (7) (11)	(9)		100	$\mu\text{s}$
$t_{\text{LOCK}}$	Time required to lock from end of device configuration (11)	10		400	$\mu\text{s}$
$f_{\text{VCO}}$	PLL internal VCO operating range	300		600 (8)	MHz
$t_{\text{LSKEW}}$	Clock skew between two external clock outputs driven by the same counter		$\pm 50$		ps
$t_{\text{SKEW}}$	Clock skew between two external clock outputs driven by the different counters with the same settings		$\pm 75$		ps
$f_{\text{SS}}$	Spread spectrum modulation frequency	30		150	kHz
% spread	Percentage spread for spread spectrum frequency (10)	0.5		0.6	%
$t_{\text{ARESET}}$	Minimum pulse width on $\text{areset}$ signal	10			ns

**Table 4–130. Enhanced PLL Specifications for -8 Speed Grade (Part 1 of 3)**

Symbol	Parameter	Min	Typ	Max	Unit
$f_{\text{IN}}$	Input clock frequency	3 (1), (2)		480	MHz
$f_{\text{INPFD}}$	Input frequency to PFD	3		420	MHz
$f_{\text{INDUTY}}$	Input clock duty cycle	40		60	%
$f_{\text{EINDUTY}}$	External feedback clock input duty cycle	40		60	%
$t_{\text{INJITTER}}$	Input clock period jitter			$\pm 200$ (3)	ps